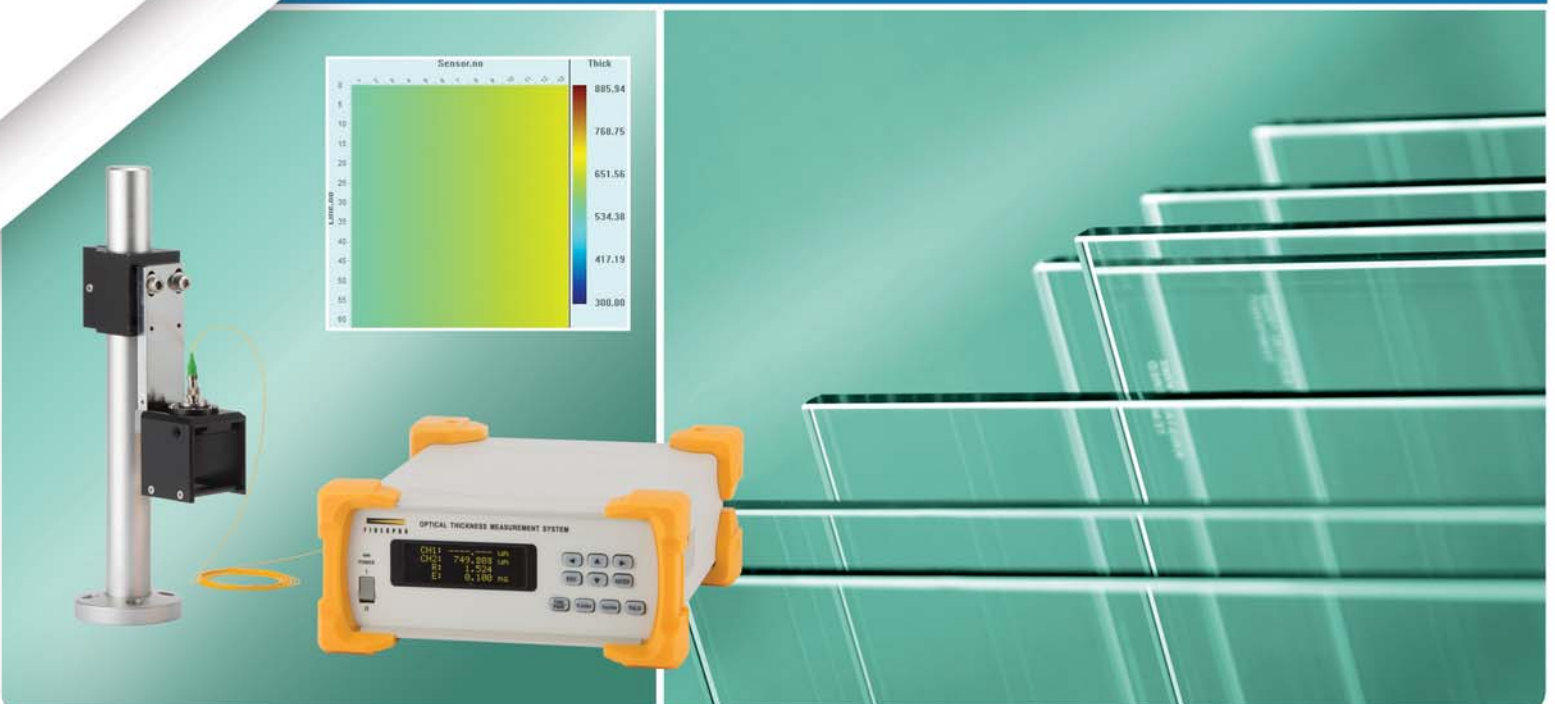


Optical Thickness Measurement System [OTMS]



High Accuracy & Repeatability
Non-contact Measurement
High Speed Measurement (~1kHz)
No Calibration Needed
Available for OEM Business and System





[TM5000]

Main Applications

- Material : Silicon wafer, Sapphire wafer, Glass wafer, SiO₂, GaAs, Others
- Industry : LCD glass panel, Glass products, Medical membrane, Others

Specifications

Measurement	
Accuracy ¹⁾	0.2um
Repeatability	0.1um
Range ³⁾	100um ~ 2,000um
Measurement Speed	Max. 1kHz
Measurement Method	Interferometric
System	
Channel	1ch, 2ch, 4ch and more
Sensor Head Working Distance	44 mm ±2 mm
Light Source	SLED (SLD)
Measurement Time	< 100sec ²⁾
Remote Interface	TCP/IP
Optical Connector Type	FC/APC
Power	Input : 100 ~ 240VAC (50/60Hz)
	Consumption : 30VA
Dimension (W x D x H)	200mm x 320mm x 85mm (without rubber cover)
	230mm x 350mm x 100mm (with rubber cover)
Weight	About 7kg

- 1) Accurate refractive index of sample must be known.
- 2) Based on the measurement of 10,000 points for 100mm wafer.
Number of measurement points and range can be customized.
- 3) Be different in accordance with material's refractive index.

< Module Name >

- TM5000 : Up to 4 ch with LCD display function
- TM5100 : Up to 4 ch without LCD display function
- TM5200 : Customized product